

## RELIABILITY MONITOR

### DS1000M-25 NOV.'97 MONITOR-OMEDATA

<b>DEVICE</b>	<b>REVISION</b>	<b>DATE CODE</b>	<b>LOT NUMBER</b>	<b>PACKAGE</b>	<b>ASSEMBLY SITE</b>
DS1000	E3	9727	DD711504ABA	8 PIN PDIP	OMEDATA
<b>PROCESS</b> Single Poly, Single Metal 1.2 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
$\beta$ : <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20931	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P20962	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P20963	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P20964	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P20965	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1000M-25 FEB '98 MONITOR-OMEDATA

<b>DEVICE</b>	<b>REVISION</b>	<b>DATE CODE</b>	<b>LOT NUMBER</b>	<b>PACKAGE</b>	<b>ASSEMBLY SITE</b>
DS1000	E3	9750	DD740614ABA	8 PIN PDIP	OMEDATA
<b>PROCESS</b> Single Poly, Single Metal 1.2 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
$\beta$ : <input type="text" value="1"/>	

JOB NO	DESCRPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21467	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21488	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21489	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21490	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21491	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1210S OCT '97 MONITOR-HYUNDAI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1210	C1	9740	DL728002AAC	16 PIN SOIC	HYUNDAI-KOREA (HEI)
<b>PROCESS</b> Single Poly, Single Metal 3.0 μ POCL3 reFlow (3um only); FLASH E2PROM (all other tech. numbers)					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20756	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P20809	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	DEVICE HRS: 3.08E+07		0
P20676	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P20810	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P20811	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P20812	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1210S JAN '98 MONITOR-HYUNDAI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1210	C1	9750	DN738347AAA	16 PIN SOIC	HYUNDAI-KOREA (HEI)
<b>PROCESS</b> Single Poly, Single Metal 3.0 μ POCL3 reFlow (3um only); FLASH E2PROM (all other tech. numbers)					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21776	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P22233	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21287	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22234	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22236	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS1232S OCT '97 MONITOR - HYUNDAI**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1232	C1	9730	DL719711ABD	16 PIN SOIC	HYUNDAI-KOREA (HEI)
<b>PROCESS</b> Single Poly, Single Metal 3.0 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
$\beta$ : <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20768	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P20817	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P20681	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P20818	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P20819	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P20820	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS1232S JAN '98 MONITOR-HYUNDAI**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1232	C1	9740	DL728793AAF	16 PIN SOIC	HYUNDAI-KOREA (HEI)
<b>PROCESS</b> Single Poly, Single Metal 3.0 μ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21326	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21403	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21246	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21404	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21405	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21406	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1233Z OCT '97 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1233	A5	9732	DM721163ACA	SOT-223	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 1.2 $\mu$ Zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
$\beta$ : <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20778	INFANT LIFE	125°C, 7.0 VOLTS	229	48	HOUR	0
P20927	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
P20687	HIGH TEMP STORAGE	125°C	233	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	233	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	233	3	PASS	0
TOTAL:						0
P20928	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P20929	HAST	120°C, 85%R.H.,5.5V	72	100	HOUR	0
TOTAL:						0
P20930	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1233Z-10 JAN '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1233	A5	9737	DM721164ABA	SOT-223	CARSEM
<b>PROCESS</b>	Single Poly, Single Metal 1.2 $\mu$ Zero tempco poly				

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21396	INFANT LIFE	125°C, 7.0 VOLTS	229	48	HOUR	0
P21440	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
P21279	HIGH TEMP STORAGE	125°C	233	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	233	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	233	3	PASS	0
TOTAL:						0
P21441	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21442	HAST	120°C, 85%R.H.,5.5V	72	100	HOUR	0
TOTAL:						0
P21443	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS1267E-50 NOV.'97 MONITOR-ANAM,PI**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1267	A1	9737	DK727730AAA	20 PIN TSSOP	ANAM-PI (AAPI)
<b>PROCESS</b> Single Poly, Single Metal 1.2 μ Implanted poly1					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20991	INFANT LIFE	125°C, 6.0V,-4.0V	234	48	HOUR	0
P21102	HIGH VOLTAGE LIFE	125°C, 6.0V,-4.0V	77	336	HOUR	0
		125°C, 6.0V,-4.0V	77	1000	HOUR	0
TOTALS:			81	DEVICE HRS: 1.13E+07		0
P20871	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21103	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21104	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			76	959	HOUR	0
TOTAL:						0
P21105	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS1302Z DEC '97 MONITOR-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1302	C1	9745	DN736077AAC	8 PIN SOIC	ANAM-KOREA (AICL)
<b>PROCESS</b> Single Poly, Double Metal 0.8 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
$\beta$ : <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21627	INFANT LIFE	125°C, 6.0 VOLTS	232	48	HOUR	0
P21731	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	336	HOUR	0
		125°C, 6.0 VOLTS	77	1000	HOUR	0
TOTALS:			81	FAIL RATE (Fits): DEVICE HRS: 1.13E+07		0
P21228	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21732	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21733	BIASED MOISTURE	85/85, 5.5 VOLTS	74	274	HOUR	0
			74	959	HOUR	0
TOTAL:						0
P21734	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS1302Z MAR '98 MONITOR-HYUNDAI,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1302	C1	9808	DL750312ABA	8 PIN SOIC	HYUNDAI-KOREA (HEI)
<b>PROCESS</b> Single Poly, Double Metal 0.8 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
$\beta$ : <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21826	INFANT LIFE	125°C, 6.0 VOLTS	229	48	HOUR	0
P21972	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	75	336	HOUR	0
		125°C, 6.0 VOLTS	75	1000	HOUR	0
TOTALS:			83	DEVICE HRS: 1.11E+07		0
P21736	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21973	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21974	BIASED MOISTURE	85/85, 5.5 VOLTS	75	274	HOUR	0
			75	959	HOUR	0
TOTAL:						0
P21975	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1315 DEC '97 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1315	B1	9737	DD724444AAC	16 PIN PDIP	OMEDATA
<b>PROCESS</b> Single Poly, Double Metal 0.8 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
$\beta$ : <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21188	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21231	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21232	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21233	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
P21234	AUTOCLAVE	121°C STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS1315 MAR '98 MONITOR-ANAM,PI**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1315	B1	9803	DK740539AAA	16 PIN PDIP	ANAM-PI (AAPI)
<b>PROCESS</b> Single Poly, Double Metal 0.8 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
$\beta$ : <input type="text" value="1"/>	

JOB NO	DESCRPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21737	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21792	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	65	336	HOUR	0
		125°C, 7.0 VOLTS	65	1000	HOUR	0
TOTALS:			35	FAIL RATE (Fits): DEVICE HRS: 2.62E+07		0
P21793	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21794	HAST	120°C, 85%R.H.,5.5V	65	100	HOUR	0
TOTAL:						0
P21795	AUTOCLAVE	121°C STEAM, UNBIASED	37	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1620S DEC '97 MONITOR-NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	C1	9740	DJ724413AAD	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)
<b>PROCESS</b> Single Poly, Single Metal 1.2 $\mu$ E2PROM process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21529	INFANT LIFE	125°C, 7.0 VOLTS	237	48	HOUR	0
P21852	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	DEVICE HRS: 3.09E+07		0
P21254	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P21853	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21854	HAST	120°C, 85%R.H.,5.5V	70	100	HOUR	0
TOTAL:						0
P22149	HIGH TEMP STORAGE	150°C	49	336	HOUR	0
			49	1000	HOUR	0
		ELEC TEST	49	1000	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1620 MAR '98 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	C1	9746	DJ723286AAC	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)
<b>PROCESS</b> Single Poly, Single Metal 1.2 $\mu$ E2PROM process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22173	INFANT LIFE	125°C, 7.0 VOLTS	232	48	HOUR	0
TOTALS:			235	FAIL RATE (Fits): DEVICE HRS: 3.89E+06		0
P22067	HIGH TEMP STORAGE	125°C	236	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	236	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	236	3	PASS	0
TOTAL:						0
P22273	HAST	120°C, 85%R.H.,5.5V	70	100	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1621S DEC '97 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A5	9740	DM727709AAA	8 PIN SOIC	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.8 $\mu$ E2PROM process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21367	INFANT LIFE	125°C, 7.0 VOLTS	236	48	HOUR	0
P21727	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21256	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P21728	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			39	1000	CYCL	0
TOTAL:						0
P21729	BIASED MOISTURE	85/85, 5.5 VOLTS	65	274	HOUR	0
			65	959	HOUR	0
TOTAL:						0
P22121	HIGH TEMP STORAGE	150°C	50	336	HOUR	0
			50	1000	HOUR	0
	ELEC TEST		50	1000	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1621S MAR '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A5	9749	DM705419ABA	8 PIN SOIC	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.8 $\mu$ E2PROM process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22276	INFANT LIFE	125°C, 7.0 VOLTS	230	48	HOUR	0
TOTALS:			242	DEVICE HRS: 3.79E+06		0
P22202	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0

## RELIABILITY MONITOR

### DS1669S-10 NOV.'97 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1669	B3	9744	DD650016AAA	8PN SOIC, 208MIL	OMEDATA
<b>PROCESS</b> Single Poly, Single Metal 1.2 $\mu$ E2PROM process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21187	INFANT LIFE	125°C, 7.0 VOLTS	232	48	HOUR	0
		ELEC TEST	38	48	HOUR	0
P21819	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	76	1000	HOUR	0
		<b>TOTALS:</b>		<b>30</b>	<b>DEVICE HRS: 3.04E+07</b>	
P20997	HIGH TEMP STORAGE MOISTURE SOAK SOLDER HEAT	125°C	238	24	HOUR	
		85°C/85% R.H.	238	168	HOUR	
		HTC VAPOR PHASE	238	3	PASS	0
		<b>TOTAL:</b>				<b>0</b>
P21820	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			35	1000	CYCL	0
		<b>TOTAL:</b>				<b>0</b>
P21821	BIASED MOISTURE	85/85, 5.5 VOLTS	73	274	HOUR	0
			69	959	HOUR	0
		<b>TOTAL:</b>				<b>0</b>
P21822	HIGH TEMP STORAGE	150°C	38	336	HOUR	0
			36	1000	HOUR	0
		ELEC TEST	36	1000	HOUR	0

## RELIABILITY MONITOR

**DS1669S-10 NOV.'97 MONITOR-OMEDATA**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1669	B3	9744	DD650016AAA	8PN SOIC, 208MIL	OMEDATA
<b>PROCESS</b> Single Poly, Single Metal 1.2 $\mu$ E2PROM process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

## RELIABILITY MONITOR

**DS17485 NOV. '97 MONITOR-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS17485	A2	9726	DN713702AAC	24 PIN SOIC	ANAM-KOREA (AICL)
<b>PROCESS</b> Single Poly, Double Metal 0.8 μ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20961	INFANT LIFE	125°C, 7.0 VOLTS	233	48	HOUR	0
P21028	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P20859	HIGH TEMP STORAGE	125°C	237	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	237	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	237	3	PASS	0
TOTAL:						0
P21029	TEMP CYCLE	-55 TO 125°C	50	300	CYCL	0
			50	1000	CYCL	0
TOTAL:						0
P21030	HAST	120°C, 85%R.H.,5.5V	65	100	HOUR	0
TOTAL:						0
P21031	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS17485 FEB.'98 MONITOR,D.P.-ANAM,K**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS17485	A2	9730	DN713701AAE	24 PIN SOIC	ANAM-KOREA (AICL)
<b>PROCESS</b> Single Poly, Double Metal 0.8 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
$\beta$ : <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22032	INFANT LIFE	125°C, 7.0 VOLTS	230	48	HOUR	0
TOTALS:			241	FAIL RATE (Fits):		0
					DEVICE HRS: 3.81E+06	
P21607	HIGH TEMP STORAGE	125°C	237	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	237	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	237	3	PASS	0
TOTAL:						0
P22305	HAST	120°C, 85%R.H.,5.5V	63	100	HOUR	0
TOTAL:						0
P22306	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2108 NOV.'97 MONTIOR,D.P.-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2108	B1	9735	DN721124AAD	24 PIN SOIC	ANAM-KOREA (AICL)
<b>PROCESS</b> Single Poly, Single Metal 5.0 μ Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20993	INFANT LIFE	125°C, 6.0 VOLTS	234	48	HOUR	0
P21077	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	336	HOUR	0
		125°C, 6.0 VOLTS	77	1000	HOUR	0
TOTALS:			81	FAIL RATE (Fits): DEVICE HRS: 1.13E+07		0
P20875	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	238	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21078	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
			40	1500	CYCL	0
TOTAL:						0
P21079	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
			77	1507	HOUR	0
TOTAL:						0
P21080	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
			37	264	HOUR	0

## RELIABILITY MONITOR

**DS2108 NOV.'97 MONTIOR,D.P.-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2108	B1	9735	DN721124AAD	24 PIN SOIC	ANAM-KOREA (AICL)
<b>PROCESS</b> Single Poly, Single Metal 5.0 μ Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

## RELIABILITY MONITOR

**DS2108 FEB.'98 MONITOR,D.P.-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2108	B1	9740	DN729120AAC	24 PIN SOIC	ANAM-KOREA (AICL)
<b>PROCESS</b> Single Poly, Single Metal 5.0 μ Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21556	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21690	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	336	HOUR	0
		125°C, 6.0 VOLTS	77	1000	HOUR	0
TOTALS:			66	DEVICE HRS: 1.38E+07		0
P21471	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21691	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21692	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21693	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2153Q DEC.'97 MONITOR,D.P.-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2153	A7	9730	DN718550AAE	44 PIN PLCC	ANAM-KOREA (AICL)
<b>PROCESS</b> Double Poly, Single Metal 0.8 μ Capacitor					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21120	INFANT LIFE	125°C, 6.0 VOLTS	233	48	HOUR	0
P21171	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	336	HOUR	0
		125°C, 6.0 VOLTS	77	1000	HOUR	0
TOTALS:			81	FAIL RATE (Fits): DEVICE HRS: 1.13E+07		0
P21096	HIGH TEMP STORAGE	125°C	237	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	237	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	237	3	PASS	0
TOTAL:						0
P21172	TEMP CYCLE	-55 TO 125°C	60	300	CYCL	0
			60	1000	CYCL	0
TOTAL:						0
P21173	AUTOCLAVE	121°C STEAM, UNBIASED	96	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2153Q MAR '98 MONITOR,D.P.-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2153	A7	9734	DN720030AAB	44 PIN PLCC	ANAM-KOREA (AICL)
<b>PROCESS</b> Double Poly, Single Metal 0.8 $\mu$ Capacitor					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
$\beta$ : <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22292	INFANT LIFE	125°C, 6.0 VOLTS	237	48	HOUR	0
TOTALS:			627	DEVICE HRS: 1.46E+06		0
P21818	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P22333	AUTOCLAVE	121°C STEAM, UNBIASED	100	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2175S JAN '98 MONITOR-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2175S	D1	9745	DN736121AAE	16 PIN SOIC	ANAM-KOREA (AICL)
<b>PROCESS</b> Single Poly, Single Metal 2.0 μ Pfield					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21487	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21612	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21340	TEMP CYCLE	-55 TO 125°C	238	10	CYCL	
	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21613	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21614	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21615	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2180A NOV.'97 MONITOR-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2180A	B3	9734	DN725581AAC	44 PIN PLCC	ANAM-KOREA (AICL)
<b>PROCESS</b> Single Poly, Single Metal 2.0 μ Pfield					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20995	INFANT LIFE	125°C, 7.0 VOLTS	235	48	HOUR	0
P21121	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
		TOTALS:	30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P20941	TEMP CYCLE	-55 TO 125°C	241	10	CYCL	
	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
		TOTAL:				0
P21122	TEMP CYCLE	-55 TO 125°C	60	300	CYCL	0
			59	1000	CYCL	0
		TOTAL:				0
P21123	HAST	120°C, 85%R.H.,5.5V	60	100	HOUR	1
		TOTAL:				1
P21124	AUTOCLAVE	121°C STEAM, UNBIASED	38	96	HOUR	0
		TOTAL:				0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
P21123	IDD	IN PROCESS				

## RELIABILITY MONITOR

**DS2181A AUG '97 MONITOR-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2181	A2	9728	DN722742ABB	44 PIN PLCC	ANAM-KOREA (AICL)
<b>PROCESS</b> Single Poly, Single Metal 2.0 μ Pfield					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20303	INFANT LIFE	125°C, 7.0 VOLTS	205	48	HOUR	0
P20458	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.03E+07		0
P20459	TEMP CYCLE	-55 TO 125°C	45	300	CYCL	0
			45	1000	CYCL	0
TOTAL:						0
P20460	HAST	120°C, 85%R.H.,5.5V	30	100	HOUR	0
TOTAL:						0
P20461	AUTOCLAVE	121°C STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2181A FEB.'98 MONITOR-ANAM,K.**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2181A	A2	9741	DN728030AAB	44 PIN PLCC	ANAM-KOREA (AICL)
<b>PROCESS</b>	Single Poly, Single Metal 2.0 $\mu$ Pfield				

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21699	INFANT LIFE	125°C, 7.0 VOLTS	237	48	HOUR	0
P21777	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.09E+07		0
P21493	TEMP CYCLE	-55 TO 125°C	241	10	CYCL	
	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P21778	TEMP CYCLE	-55 TO 125°C	60	300	CYCL	0
			60	1000	CYCL	0
TOTAL:						0
P21779	HAST	120°C, 85%R.H.,5.5V	60	100	HOUR	0
TOTAL:						0
P21780	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS21S07AE NOV.'97 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS21S07	E	9732	DM717607ABA	20 PIN TSSOP	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.8 μ Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20970	INFANT LIFE	125°C, 7.0 VOLTS	232	48	HOUR	0
P21024	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P20873	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21025	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21026	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			75	959	HOUR	0
TOTAL:						0
P21027	AUTOCLAVE	121°C STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS21S07A FEB '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS21S07	E	9802	DM741735ABC	20 PIN TSSOP	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.8 $\mu$ Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
$\beta$ : <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21637	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21694	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	DEVICE HRS: 3.08E+07		0
P21469	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21695	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21696	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21697	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS232 DEC '97 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS232	B3	9742	DD734647ABF	16 PIN PDIP	OMEDATA
<b>PROCESS</b> Single Poly, Single Metal 5.0 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21091	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21152	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21153	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21154	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21155	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS232 MAR '98 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS232	B3	9809	DD747723AAB	16 PIN PDIP	OMEDATA
<b>PROCESS</b> Single Poly, Single Metal 5.0 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21726	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21751	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21752	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21753	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21754	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS2401 DEC '97 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	A2	9739	DM730233ABA	T0-92	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 1.2 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21090	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21143	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21144	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21145	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
P21146	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS2401 MAR '98 MONITOR-CARSEM**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9802	DM741755ACA	T0-92	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.8 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22162	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
		<b>TOTALS:</b>			<b>FAIL RATE (Fits):</b>	34
P22163	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
		<b>TOTAL:</b>				
P22164	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
		<b>TOTAL:</b>				
P22165	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
		<b>TOTAL:</b>				

## RELIABILITY MONITOR

### DS2401 MAR '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9802	DM741755ACA	T0-92	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.8 $\mu$ Standard Process					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22152	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
TOTALS:			234	3.91E+06	DEVICE HRS:	0
P22163	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22164	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
P22165	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS2502S DEC.'97 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	B2	9743	DM731253AAB	8 PIN SOIC	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 0.8 $\mu$ EPROM process					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
$\beta$ : <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21290	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21313	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21169	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
	ELECTRICAL TEST	ELEC TEST	238	0		0
TOTAL:						0
P21314	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21315	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21316	HIGH TEMP STORAGE	150°C	40	336	HOUR	0
			40	1000	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS5002 OCT '97 MONITOR,D.P.-CARSEM**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002	B3	9738	DM722224AAB	80 PIN PQFP	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 1.2 $\mu$ Buried contacts w/silicided poly					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
$\beta$ : <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20758	INFANT LIFE	125°C, 7.0 VOLTS	199	48	HOUR	0
P20837	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.02E+07		0
P20706	HIGH TEMP STORAGE	125°C	203	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	203	3	PASS	0
TOTAL:						0
P20838	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P20839	BIASED MOISTURE	85/85, 5.5 VOLTS	42	274	HOUR	0
			42	959	HOUR	0
TOTAL:						0
P20840	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

### DS5002F JAN.'98 MONITOR,D.P.-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002F	A3	9738	DM720028AAC	80 PIN PQFP	CARSEM
<b>PROCESS</b> Single Poly, Single Metal 1.2 $\mu$ Buried contacts w/silicided poly					

Summary Data with Chi-Square Distribution Assumed.  
 Stress Ambient Temperature and Voltage to  
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
$\beta$ :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21352	INFANT LIFE	125°C, 7.0 VOLTS	199	48	HOUR	0
TOTALS:			275	3.34E+06	DEVICE HRS:	0
P21282	HIGH TEMP STORAGE	125°C	203	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	203	3	PASS	0
TOTAL:						0
P21472	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21474	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

## RELIABILITY MONITOR

**DS80C320 JUN '97 MONITOR,D.P-ANAM,K**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS80320	B5	9718	DN708196AAX	44 PIN PLCC	ANAM-KOREA (AICL)
<b>PROCESS</b> Single Poly, Single Metal 0.8 μ Poly silicide					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P19846	INFANT LIFE	125°C, 7.0 VOLTS	231	48	HOUR	0
P19923	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P19924	TEMP CYCLE	-55 TO 125°C	49	300	CYCL	0
			49	1000	CYCL	0
TOTAL:						0
P19925	HAST	120°C, 85%R.H.,5.5V	60	100	HOUR	1
TOTAL:						1
P19926	AUTOCLAVE	121°C STEAM, UNBIASED	45	96	HOUR	0
TOTAL:						0

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
P19925	ICCSP_IN	IN PROCESS	

## RELIABILITY MONITOR

**DS80C320 SEP '97 MONITOR,D.P-ANAM,K**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS80320	B5	9718	DN710449AAB	44 PIN PLCC	ANAM-KOREA (AICL)
<b>PROCESS</b> Single Poly, Single Metal 0.8 μ Poly silicide					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P20466	INFANT LIFE	125°C, 7.0 VOLTS	231	48	HOUR	0
P20546	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	1
		125°C, 7.0 VOLTS	76	1000	HOUR	0
TOTALS:			66	DEVICE HRS: 3.04E+07		1
P20547	TEMP CYCLE	-55 TO 125°C	49	300	CYCL	0
			49	1000	CYCL	0
TOTAL:						0
P20548	HAST	120°C, 85%R.H.,5.5V	60	100	HOUR	0
TOTAL:						0
P20549	AUTOCLAVE	121°C STEAM, UNBIASED	45	96	HOUR	0
TOTAL:						0

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
P20546	ICCSP_IN	IN PROCESS	

## RELIABILITY MONITOR

**DS80320 JAN '98 MONITOR-ANAM PI**

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS80320	B5	9749	DK739467AAA	40 PIN PDIP	ANAM-PI (AAPI)
<b>PROCESS</b> Single Poly, Single Metal 0.8 $\mu$ Poly silicide					

Summary Data with Chi-Square Distribution Assumed.  
Stress Ambient Temperature and Voltage to  
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
$\beta$ : <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21300	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21353	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21354	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21355	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	1
TOTAL:						1
P21356	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
P21355	ICCSP_IN	IN PROCESS	